


Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement</b> by Applicant (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office <b>MAR 29 2002</b>	Attorney's Docket No. 09712-055001	Application No. 10/025,595
	Applicant Peter de Groot		
	Filing Date December 18, 2001	Group Art Unit	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>all</i>	AA	4,340,306	07/20/82	Balasubramanian			
	AB	4,869,593	09/26/89	Biegen			
	AC	5,239,178	08/24/93	Demdinger et al.			
	AD	5,398,113	03/14/95	de Groot			
	AE	5,737,084	04/07/98	Ishihara			

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation <input type="checkbox"/> Yes <input type="checkbox"/> No
	AF						

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
<i>all</i>	AG	Caber, Paul J., "Interferometric Profiler for Rough Surfaces", <i>Applied Optics</i> , Vol. 32, No. 19, July 1, 1993, pp. 3438-3441
	AH	Dresel, Thomas et al., "Three-dimensional sensing of rough surfaces by coherence radar", <i>Applied Optics</i> , Vol. 31, No. 7, March 1, 1992, pp. 919-925
	AI	Tiziani H.J. et al., "Chromatic confocal microscopy with microlenses", <i>Journal of Modern Optics</i> , Vol. 43, No. 1, 1996, pp. 155-163
	AJ	Tiziani H.J. et al., "Three-dimensional analysis by a microlens-array confocal arrangement", <i>Applied Optics</i> , Vol. 33, No. 4, February 1, 1994, pp. 567-572

Examiner Signature 	Date Considered 2/22/05
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	